Issue Classification

Application/Control No.	Applicant(s)/Patent Under Reexamination
10757115	SMITH ET AL.
Examiner	**Art Unit**
Nguyen, Hiep	2816

ORIGINAL		INTERNATIONAL CLASSIFICATION										
CLASS	SUBCLASS	CLAIMED					NON-CLAIMED					
327	108	H	0	3	K	3/00						

CROSS REFERENCE(S)					
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
327	109	110	111	112	538
326	82	83	84	85	86

Hiep Nguyen (Assistant Examiner)	06-14-07 (Date)		**Total Claims Allowed:** 20
(Legal Instruments Examiner)	6/14/07 (Date)	TUAN T. LAM PRIMARY EXAMINER (Primary Examiner) (Date) 6/14/07	O.G. Print Claim(s) 1 / O.G. Print Figure 1